

EE 315

Final Project

Thomas Flores and Samuel Lenius

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I. INTRODUCTION

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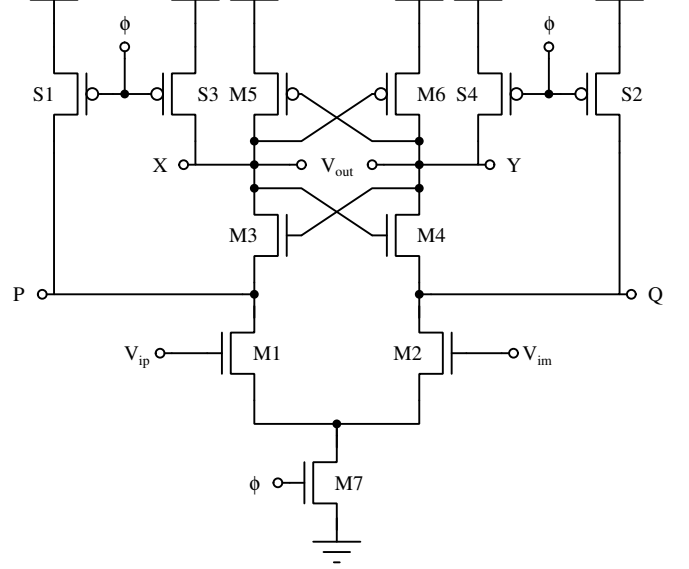


Fig. 1. Circuit topology for the strong arm latch comparator.

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II. COMPARATOR

Proper optimization of the comparator element in the SAR ADC will provide the greatest improvement in our figure of merit, as it will ultimately set the maximum speed of our design. Given that our figure of merit is proportional to the power consumed for each decision, the ideal design includes a dynamic comparator which only draws current during the decision time. For this reason, we choose the Strong Arm Latch [1] for its energy efficiency and simple design.

To size our comparator to first order, we begin by considering the required noise specification of the total SAR ADC. We can derive the maximum noise power for our full-scale signal power as

$$\sigma_{n,in}^2 = \frac{P_{sig}}{10^{SNR_{spec}/10}} = \frac{(0.5V_{FS})^2}{10^{\frac{SNR_{spec}}{10}}} \quad (1)$$

Because we are designing to first order and expect some noise contribution from the other blocks, we impose a slightly higher noise spec of 60 dB. This gives an input referred noise requirement of $\sigma_{n,in} = 707.11 \mu V_{RMS}$ for $V_{FS} = 2 V$.

We approximate the input referred noise for the strong arm latch as

$$\sigma_{n,in}^2 \approx \frac{8\gamma}{A_v} \frac{kT}{C_{P,Q}} \quad (2)$$

where the gain A_v during the amplification phase can be approximated as

$$A_v \approx \frac{g_{m1,2}}{I_D} V_{tn} \quad (3)$$

We select $\frac{g_m}{I_D} = 15$ as this provides a reasonable tradeoff between speed and power of the transistor (SHOW CURVE?). From simulations, we find that the approximate threshold voltage $V_{tn} \approx 250$ mV for our nmos devices. We can then solve for the minimum capacitance necessary nodes P and Q using Equations 2, 3, and $\sigma_{n,in} = 707 \mu\text{V}_{\text{RMS}}$

$$C_{P,Q} \geq \frac{8\gamma}{A_v} \frac{kT}{\sigma_{n,in}^2} \rightarrow C_{P,Q} \geq 14.79 \text{ fF} \quad (4)$$

To begin our design, we create a unit comparator constructed from some reasonable design choices. To maximize speed in the cross coupled inverters, we assume that pmos elements M5,6 should be twice the width of the nmos elements M3,4. To size M3,4, we must limit the widths so they do not significantly contribute to the mismatch at the input. For our design with $A_v \approx 3.5$, this means that $W_{3,4} \geq \frac{1}{3.5} W_{1,2}$ due to the offset referral to the input.

TABLE I
DEFAULT

test	test
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III. TRACK AND HOLD

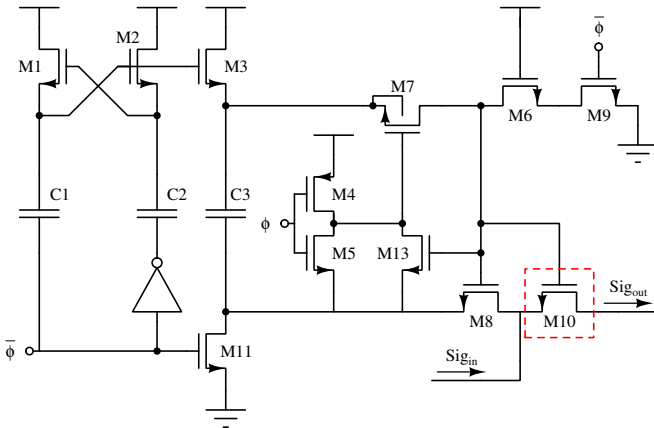


Fig. 2. Circuit topology for the bootstrapped switch for improved linearity.

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REFERENCES

- [1] B. Razavi, "The StrongARM Latch [A Circuit for All Seasons]," *IEEE Solid-State Circuits Magazine*, vol. 7, no. 2, pp. 12–17. [Online]. Available: <http://ieeexplore.ieee.org/document/7130773/>